Cascade PMV200

200 mm Manual Vacuum Probe System

Overview

Cascade PMV200 probe system from FormFactor is the ideal solution for testing wafers and substrates up to 200 mm in a high vacuum environment < 1×10^4 mbar. It supports a wide temperature range from -60°C to 300°C. Specially designed for laboratory requirements, it supports a wide range of applications, including DC and RF measurements, MEMS and opto-engineering tests.

The PMV200 is equipped with a stable vibration isolating frame. The chuck and the manual chuck stage with 200 mm x 200 mm X-Y travel, theta and Z-axis are located inside the high-vacuum chamber. Via vacuum-tight mechanical feedthrough drives and cardan shafts, the X-Y travel, contact/separation and up to eight vacuum-type positioners can be easily operated from outside of the chamber. For the use under vacuum conditions, specially-designed thermal chucks with electrical and cooling line bulk-feedthroughs are available.



The PMV200 can be customized with a number of instruments, including various video microscopes, optical topology measurement tools and black bodies for exposure of the DUT with controlled IR radiation.

> Features / Benefits

Flexibility	 System is customized to user's requirements Different substrate carriers for wafers up to 200 mm or single dies Upstream pressure, downstream pressure or medium vac regulation Wide range of measurements (I-V, C-V, RF) Accessories available, such as Black Bodies and optical motion analysis tools
Stability	High accuracy, ideal for small structuresHighly stable mechanics with a stable vibration isolation table
Ease of use	 Simple, straightforward design for easy and ergonomic operation Quick and ergonomic change of the DUT through front door
High measurement throughput	Manual control of chuck for fast step-and-repeat testing of the entire wafer



> Specifications*

Chuck Stage	
Travel range	200 mm (round or square)
Resolution	5 μm
Manipulation	Linear, from outside the chamber via rotary feed thru drives
Probe Platen	
Platen space	Universal platen for up to six VCP110 positioners
Z contact / separation	About 250 μm
Manipulation	From outside the chamber
Microscope	
Travel	Swivel mechanism for moving the microscope in a safe rest position for chamber opening
Focus	Manual drive
Туре	Video zoom microscope
Zoom	7x
Magnification	0.38x to 2.6x
Resolution	721 lp/mm to 240 lp/mm
Field of view	12.8 mm x 17.1 mm to 1.8 mm x 2.4 mm
Chuck Standard Chuck	No temperature control, holds carrier for fixing single chips, wafer fragments and full wafer up to 200 mm
Standard Chuck	No temperature control, flords carrier for fixing single crips, water fragments and full water up to 200 film
Thermal Chuck	
Minimum temperature	-60°C, -40°C, 25°C
Maximum temperature	200°C, 300°C
Vacuum Chamber	
Size	Approximately ø 600 mm x 300 mm (H)
Material	Stainless steel
Loading	Hinged top side lid, made of aluminum, fast lock mechanism
View port	Central, top side, made of ø 90 mm quartz glass, 6 mm thickness, ø 75 mm clear opening, minimum objective working distance 75 mm
Feedthrough	
Chamber wall:	 6x DN50 ISO-KF flange for rotary feedthrough drives to operate VCP110 probe positioners from outside
	 2x DN50 ISO-KF flange for rotary feedthrough drives for operating chuck XY stage from outside
	 1x DN50 ISO-KF flange for rotary feedthrough drive for operating platen contact/separation drive from outside
	2x DN50 ISO-KF flange for measurement feedthroughs
	1x DN25 ISO-KF flange with safety valve
	 1x DN10 ISO-KF flange for venting valve, manually operated

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> Specifications* (continued)

Chamber bottom plate:

	1x DN63 ISO-K flange for turbo-molecular drag pump	
	 2x DN40 ISO-KF flange (1x for optional thermal chuck, 1x spare) 	
	1x DN25 ISO-KF flange for vacuum gauge	
	• 1x DN16 ISO-KF flange (spare)	
	 6x WDE105 feedthrough (1x for optional thermal chuck, 5x spare) 	
	1x D28 opening (spare)	
Purging	Manual operated inlet valve to fill the vacuum chamber with inert gas (N2)	
Carrier	F2 75 400 450 000	
Wafer carrier	50 mm, 75 mm, 100 mm, 150 mm, 200 mm	
Universal carrier	Small dies, wafer fragments	
Positioner		
Туре	VCP110 high vacuum type probe positioner	
Travel range	X, Y and Z = 12 mm linear	
Fixation	Magnetic	
Manipulation	From outside the chamber via rotary feed thru drives	
Measurement Setup		
Probe arms	Triax, advanced coax and high frequency	
Cabling	Triax, advanced coax and high frequency (40 GHz, 50 GHz and 67 GHz)	
Feedthrough	Triax, advanced coax and high frequency (40 GHz, 50 GHz and 67 GHz)	
Triax chuck	For low-noise I-V and C-V measurements	
High Vacuum System		
Minimum pressure	<1 x 10 ⁻⁴ mbar	
Maximum pressure	Atmosphere	
Pump type	Turbo and diaphragm	
Vacuum gauge	Full range	
Pressure control system	Optional, up-stream controlled	
TV System		
USB	Digital camera connection to computer	
HDMI	Digital camera connection to monitor	
Microscope Upgrade		
Movement	Upgrade from default boom stand to high resolution XY microscope movement	
Microscope	Upgrade from default video zoom microscope to high-magnification compound microscope	
View-port		
Customized window	For applications where the standard window does not meet the requirements, other windows available with different window material, AR coating, working distance and diameter.	
* Data, design and specification depend on individual process conditions and can vary according to equipment configurations.		

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• 1x DN100 ISO-K flange for measurement feedthroughs



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Data, design and specification depend on individual process conditions and can vary according to equipment configuration.
 Not all specifications may be valid simultaneously.

> Applications

MEMS / MOEMS

Acceleration sensors

RF-MEMS switches, resonators

Microbolometers

Yaw rate sensors / gyro sensors

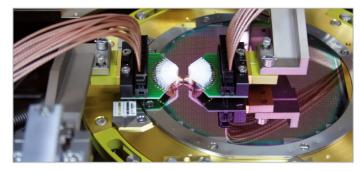
Gas sensors

Micromirrors / optical switches

Next Generation Technologies

OLEDs

Nanotechnology



Test of a MEMS wafer with two Multi DC ProbeWedges™.

> Handling

All knobs located outside of the chamber ensure easy and precise control of the chuck stage and positioners. The hinged front door enables quick and ergonomic loading and unloading of the DUT. The chamber lid allows easy probe configuration and probe tip exchange.



The large front door enables quick and ergonomic loading and unloading of the DUT. The chuck and up to eight vacuum-type positioners can be easily operated from outside of the chamber via universal joint drivers.



View through the view port of the chamber lid. The shown configuration consists of four RF IZI Probes® and four DC probes.

> Ordering Information

Part Number	Description
PMV200DC-QT	Manual vacuum probing solution for DC test includes the PMV200 package, four DC triax positioners, probe tips, feedthrough and cabling
PMV200RF-QT	Manual vacuum probing solution for RF test includes the PMV200 package, two RF positioners, IZI Probes, feedthrough and cabling

The offered PMV200 packages include all required components for successful probing:

- PMV200 base system with a chuck movement of 200 mm
- · High-vacuum pump station
- Substrate carrier for the required sample size
- · Microscope with camera and monitor

> Warranty

Warranty*	Fifteen months from date of delivery or twelve months from date of installation
Service contracts	Single- and multi-year programs available to suit your needs

See FormFactor's Terms and Conditions of Sale for more details.

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